

Notice of References Cited

Application/Control No.

10/800,612

Applicant(s)/Patent Under
Reexamination
YOSHIDA ET AL.

Examiner

Qing-Yuan Wu

Art Unit

2194

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-5,668,988	09-1997	Chen et al.	707/101
*	C	US-7,117,191	10-2006	Gavan et al.	706/47
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	M	US-			

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Teng et al., "Adaptive Real-time Anomaly Detection Using Inductively Generated Sequential Patterns", 1990, IEEE, pgs. 278-284.
	V	Teng et al., "Security Audit Trail Analysis Using Inductively Generated Predictive Rules", 1990, IEEE, pgs. 24-29.
	W	Lee et al., "Data Mining Approaches for Intrusion Detection", 2000, ACM, pgs. 1-15
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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